Boundary-Scan Architecture and compliance to the IEEE Std 1149.1

The dedicated test access port (TAP) is fully compliant to the IEEE Std. 1149.1. It consists of 5 dedicated signal pins, a 16-state TAP Controller and three test da

through the appropriate states shown in **Figure 2**. The states of the data register scan and instruction register scan blocks .ae 2mirror imags of teach ohe r, adding symmetry tothe droptocol sequences The sfirst ation rthat occurs when eihe r

Figure 4: Output Cell